

S1: (arrow marks, CX) AR<0.1% @ 1020 - 1040 nm, AOI=0 deg
S2: (PL) AR<0.1% @ 1020 - 1040 nm, AOI=0 deg

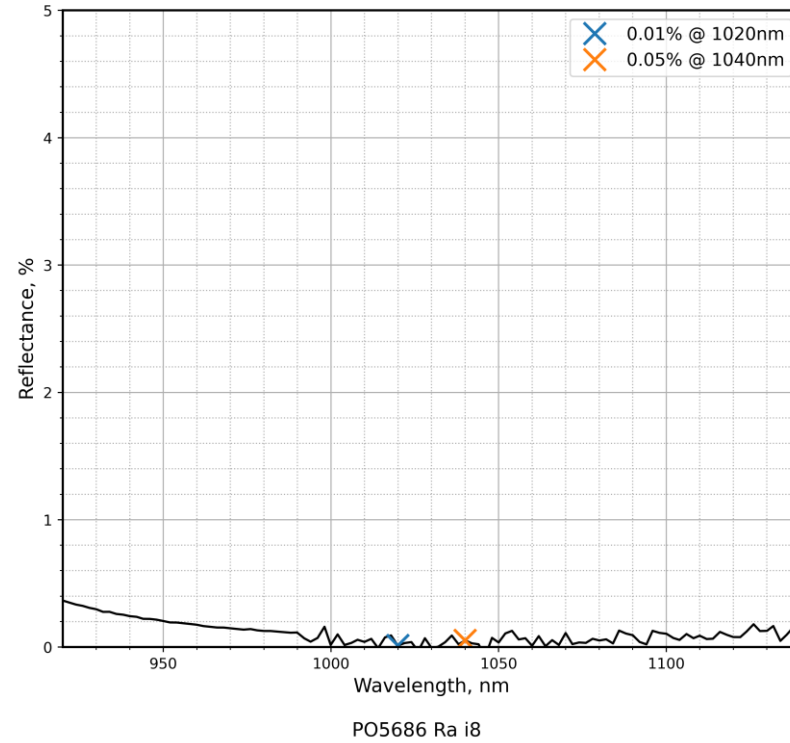


Fig. 1.

SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%

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S2: (PL) AR<0.1% @ 1020 - 1040 nm, AOI=0 deg

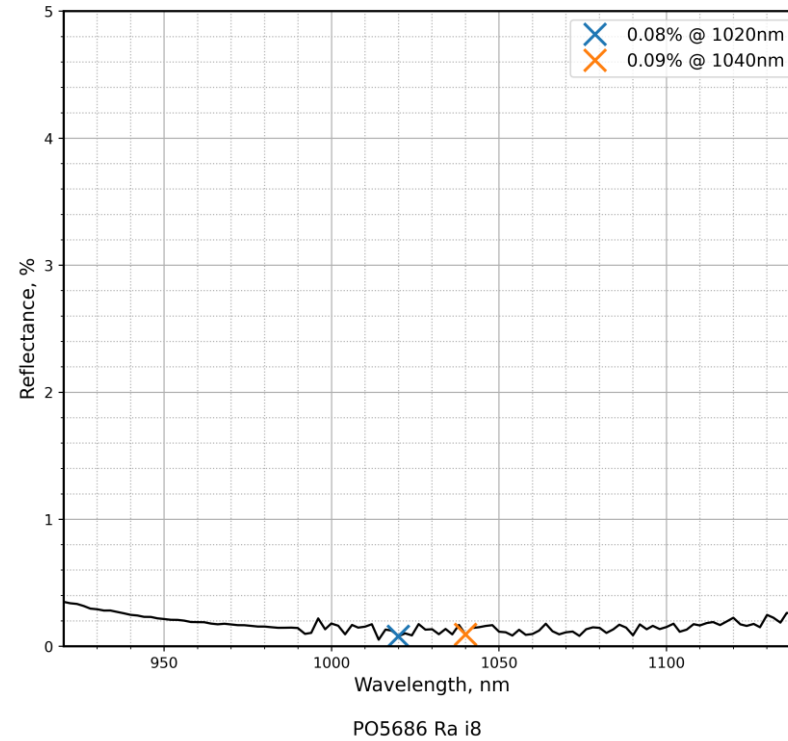


Fig. 2.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%